

# FAST CMOS OCTAL TRANSPARENT LATCH

# IDT74FCT373T/AT/CT/DT

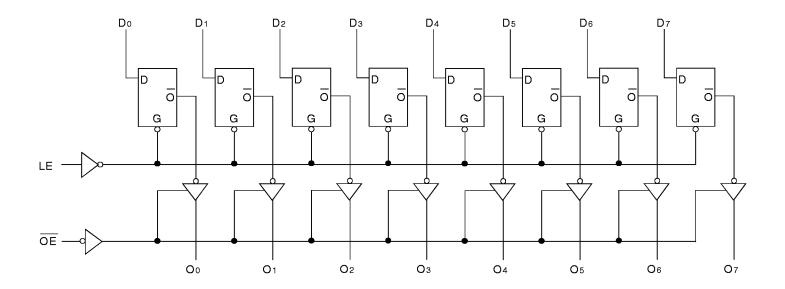
## **FEATURES:**

- Low input and output leakage  $\leq 1 \mu A$  (max.)
- Extended commercial range of -40°C to +85°C
- CMOS power levels
- True TTL input and output compatibility
  - VOH = 3.3V (typ.)
  - VoL = 0.3V (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Available in PDIP, SOIC, SSOP, QSOP, and TSSOP packages
- Std., A, C and D speed grades
- High drive outputs (-15mA loн, 48mA loL)
- Power off disable outputs permit "live insertion"

## **DESCRIPTION:**

The FCT373Tis an octal transparent latch built using an advanced dual metal CMOS technology. These octal latches have 3-state outputs and are intended for bus oriented applications. The flip-flops appear transparent to the data when Latch Enable (LE) is high. When LE is low, the data that meets the set-up time is latched. Data appears on the bus when the Output Enable  $(\overline{OE})$  is low. When  $\overline{OE}$  is high, the bus output is in the high-impedance state.

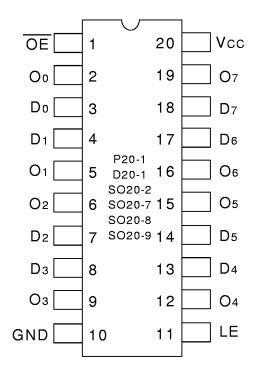
# FUNCTIONAL BLOCK DIAGRAM



### **COMMERCIAL TEMPERATURE RANGE**

### SEPTEMBER 1999

## **PIN CONFIGURATION**



PDIP/ SOIC/ SSOP/ QSOP/ TSSOP/ CERPACK TOP VIEW

### COMMERCIALTEMPERATURERANGE

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Rating	Max.	Unit
VTERM <sup>(2)</sup>	Terminal Voltage with Respect to GND	–0.5 to +7	V
VTERM <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to Vcc+0.5	۷
Тѕтс	Storage Temperature	–65 to +150	°C
Ιουτ	DC Output Current	-65 to +120	mA
			8T-link

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
- 2. Inputs and Vcc terminals only.
- 3. Outputs and I/O terminals only.

## **CAPACITANCE** (TA = $+25^{\circ}$ C, f = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Тур.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	6	10	рF
Соит	Output Capacitance	Vout = 0V	8	12	pF
	-				8T-link

NOTE:

1. This parameter is measured at characterization but not tested.

## PIN DESCRIPTION

Pin Names	Description			
DN	Data Inputs			
LE	Latch Enable Input (Active HIGH)			
OE Output Enable Input (Active LOW)				
ON	3-State Outputs			

### **FUNCTION TABLE (1)**

	Outputs		
DN	LE	OE	ON
Н	Н	L	L
L	Н	L	Н
X	Х	Н	Z

NOTE:

1. H = HIGH Voltage Level

L = LOW Voltage Level

X = Don't Care

Z = High-Impedance

### **DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE**

Following Conditions Apply Unless Otherwise Specified:

Commercial:  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ ,  $V_{CC} = 5.0V \pm 5\%$ 

Symbol	Parameter	Test Conditions <sup>(1)</sup>			Typ. <sup>(2)</sup>	Max.	Unit
Vih	Input HIGH Level	Guaranteed Logic HIGH Leve	el	2	-		V
Vi∟	Input LOW Level	Guaranteed Logic LOW Leve	9	_	—	0.8	V
Ін	Input HIGH Current <sup>(4)</sup>	Vcc = Max.	VI = 2.7V	_	_	±1	μA
lı L	Input LOW Current <sup>(4)</sup>		VI = 0.5V	_	—	±1	μA
lozн	High Impedance Output Current	Vcc = Max. Vo = 2.7V		_	_	±1	μA
lozl	(3-State output pins) (4)	Vo = 0.5V		_	_	±1	
l	Input HIGH Current	Vcc = Max., VI = Vcc (Max.)		_	_	±1	μA
Vik	Clamp Diode Voltage	Vcc = Min., IIN = -18mA		_	-0.7	-1.2	V
Vн	Input Hysteresis	-		_	200	_	mV
lcc	Quiescent Power Supply Current	VCC = Max., VIN = GND or VC	C	_	0.01	1	μA

# **OUTPUT DRIVE CHARACTERISTICS**

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
Vон	Output HIGH Voltage	Vcc = Min.	Iон = -8mA	2.4	3.3		V
		VIN = VIH or VIL	Іон = –15mA	2	3	Ι	
Vol	Output LOW Voltage	Vcc = Min. IoL = 48mA		_	0.3	0.5	V
		VIN = VIH or VIL					
los	Short Circuit Current	Vcc = Max, Vo = GND <sup>(3)</sup>		-60	-120	-225	mA
IOFF	Input/Output Power Off Leakage <sup>(5)</sup>	Vcc = 0V, VIN or Vo $\leq$ 4.5V		_	_	±1	mA

#### NOTES:

For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
 Typical values are at Vcc = 5.0V, +25°C ambient and maximum loading.

3. Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.

4. The test limit for this parameter is  $\pm 5\mu$ A at TA =  $-55^{\circ}$ C.

5. This parameter is guaraneteed but not tested.

### COMMERCIALTEMPERATURERANGE

## **POWER SUPPLY CHARACTERISTICS**

Symbol	Parameter	Test	Test Conditions <sup>(1)</sup>		Typ. <sup>(2)</sup>	Max.	Unit
	Quiescent Power Supply Current TTL Inputs HIGH	Vcc = Max. VIN = 3.4V <sup>(3)</sup>		-	0.5	2	mA
ICCD	Dynamic Power Supply Current <sup>(4)</sup>	Vcc = Max. Outputs Open $\overline{OE}$ = GND One Input Toggling 50% Duty Cycle	VIN = VCC VIN = GND	-	0.15	0.25	mA/ MHz
lc	Total Power Supply Current <sup>(6)</sup>	Vcc = Max. Outputs Open fi = 10MHz 50% Duty Cycle OE = GND LE = Vcc One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = GND$ $V_{IN} = 3.4$ $V_{IN} = GND$	-	1.5	3.5 4.5	mA
		Vcc = Max. Outputs Open fi = 2.5MHz	VIN = VCC VIN = GND	-	3	6 <sup>(5)</sup>	
		50% Duty Cycle OE = GND LE = Vcc Eight Bits Toggling	VIN = 3.4 VIN = GND	-	5	14 <sup>(5)</sup>	

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at Vcc = 5.0V, +25°C ambient.

3. Per TTL driven input (VIN = 3.4V); all other inputs at Vcc or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of the Icc formula. These limits are guaranteed but not tested.

6. IC = IQUIESCENT + INPUTS + IDYNAMIC

 $IC = ICC + \Delta ICC DHNT + ICCD (fCP/2 + fiNi)$ 

Icc = Quiescent Current

 $\Delta Icc$  = Power Supply Current for a TTL High Input (VIN = 3.4V)

DH = Duty Cycle for TTL Inputs High

NT = Number of TTL Inputs at DH

ICCD = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

fcp = Clock Frequency for Register Devices (Zero for Non-Register Devices)

fi = Input Frequency

Ni = Number of Inputs at fi

All currents are in milliamps and all frequencies are in megahertz.

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## SWITCHING CHARACTERISTICS OVER OPERATING RANGE

			FCT	373 <b>T</b>	FCT3	373 <b>AT</b>	FCT3	73 <b>CT</b>	FCT3	873DT	
Symbol	Parameter	Conditions <sup>(1)</sup>	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Unit
tplн tpнL	Propagation Delay Dn to On	CL = 50pF RL = 500Ω	1.5	8	1.5	5.2	1.5	4.2	1.5	3.8	ns
tрін tрні	Propagation Delay LE to ON		2	13	2	8.5	2	5.5	2	4	ns
tPZH tPZL	Output Enable Time		1.5	12	1.5	6.5	1.5	5.5	1.5	4.8	ns
tPHZ tPLZ	Output Disable Time		1.5	7.5	1.5	5.5	1.5	5	1.5	4	ns
tsu	Set-up Time HIGH or LOW, DN to LE		2	_	2	_	2		1.5	_	ns
tн	Hold Time HIGH or LOW, DN to LE		1.5	_	1.5	_	1.5	_	1	_	ns
tw	LE Pulse Width HIGH <sup>(3)</sup>		6	_	5	_	5	_	3	_	ns

#### NOTES:

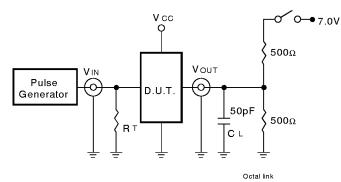
1. See test circuit and wave forms.

Minimum limits are guaranteed but not tested on Propagation Delays.
 This parameter is guaranteed but not tested.

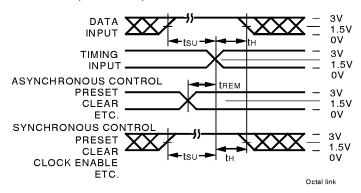
### COMMERCIALTEMPERATURERANGE

### **TEST CIRCUITS AND WAVEFORMS**

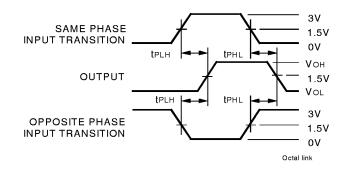
## **TEST CIRCUITS FOR ALL OUTPUTS**



### SET-UP, HOLD, AND RELEASE TIMES



# **PROPAGATION DELAY**



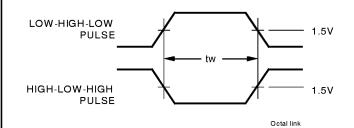
# **SWITCH POSITION**

Test	Switch
Open Drain	
Disable Low	Closed
Enable Low	
All Other Tests	Open
	8-link

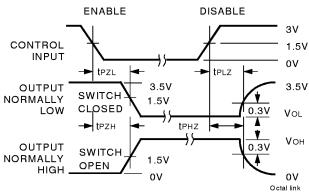
### DEFINITIONS:

- CL = Load capacitance: includes jig and probe capacitance.
- RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

## **PULSE WIDTH**



## **ENABLE AND DISABLE TIMES**

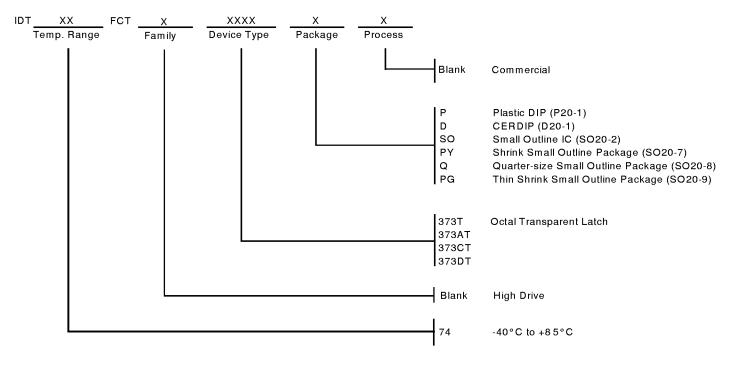


#### NOTES:

- 1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- 2. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; tF ≤ 2.5ns; tR ≤ 2.5ns

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### **ORDERING INFORMATION**





*CORPORATE HEADQUARTERS* 2975 Stender Way Santa Clara, CA 95054 for SALES: 800-345-7015 or 408-727-6116 fax: 408-492-8674 www.idt.com\*

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